

<b>Notice of References Cited</b>	Application/Control No. 10/717,888	Applicant(s)/Patent Under Reexamination HAYNES ET AL.	
	Examiner Eric A. Wiener	Art Unit 2112	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,139,762	11-2006	Labarge et al.	707/100
*	B	US-5,630,122	05-1997	Kaplan et al.	707/4
*	C	US-6,269,407	07-2001	Cink et al.	719/315
*	D	US-6,049,783	04-2000	Segal et al.	705/37
*	E	US-5,956,508	09-1999	Johnson et al.	719/315
*	F	US-5,838,317	11-1998	Bolnick et al.	715/764
*	G	US-5,809,483	09-1998	Broka et al.	705/37
*	H	US-5,566,330	10-1996	Sheffield, Kim A.	707/4
*	I	US-5,787,411	07-1998	Groff et al.	707/2
*	J	US-5,710,899	01-1998	Eick, Stephen Gregory	715/764
*	K	US-5,680,563	10-1997	Edelman, Bradley A.	715/835
*	L	US-5,519,865	05-1996	Kondo et al.	707/1
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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